

Applied MDLx™ Ginestra™ Simulation Software ReRAM Capabilities – V3.1

- Charge trapping and transport within dielectrics
- Charge transport in pristine, high-resistance and low-resistance states (or a combination of them)
- Power dissipation and temperature increase
- Generation of oxygen vacancies and ions
- Motion and recombination of vacancies and ions
- Material modifications with changes in material stoichiometry
 - Dielectric constant
 - Thermal conductivity
- Reliability
 - Endurance
 - Retention
 - Variability

